

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  <i>(Multiple sheets used when necessary)</i>	Application No.	10/576,405
	Filing Date	April 30, 2007
	First Named Inventor	Hada et al.
	Art Unit	1795
SHEET 1 OF 2		Examiner
		Anca Eoff
		Attorney Docket No.
		SHIGA7.048APC

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
/A.E./	1	2004/0186216	09-23-2004	Satoh et al.	
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	5	5,968,713	10-19-1999	Nozaki et al.	Corresponds to No. 26
	6	6,656,659	12-02-2003	Nozaki et al.	Corresponds to No. 27
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	8	5,554,664	09-10-1996	Lamanna et al.	
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/A.E./	16	WO 2002/077116	10-03-2002	Daikin Industries, Ltd.		√ abstract
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	19	JP 2004-057449	02-26-2004	Matsushita Electric Ind Co Ltd		√
	20	JP H07-234511	09-05-1995	Fujitsu Ltd		√ abstract
	21	JP H09-073173	03-18-1997	Fujitsu Ltd		√ abstract
	22	JP H09-090637	04-04-1997	Fujitsu Ltd		√ abstract
↓	23	JP H11-012326	01-19-1999	Fujitsu Ltd		√ abstract
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Examiner Signature	/Anca Eoff/	Date Considered	03/17/2009
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\***Examiner:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

T<sup>1</sup> - Place a check mark in this area when an English language Translation is attached.

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/A.E./	25	JP H05-346668	12-27-1993	Fujitsu Ltd		√ abstract
↓	26	JP H10-161313	06-19-1998	Fujitsu Ltd		√ abstract
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/A.E./	29	JP 2002-311587	10-23-2002	Fujitsu Ltd		√ abstract

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>1</sup>
/A.E./	30	PRZYBILLA K.J. et al., "Hexafluoroacetone in Resist Chemistry: A Versatile New Concept for Materials for Deep UV Lithography", <i>SPIE Vol. 1672 Advances in Resist Technology and Processing IX</i> (1992), pages 500-512.	

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